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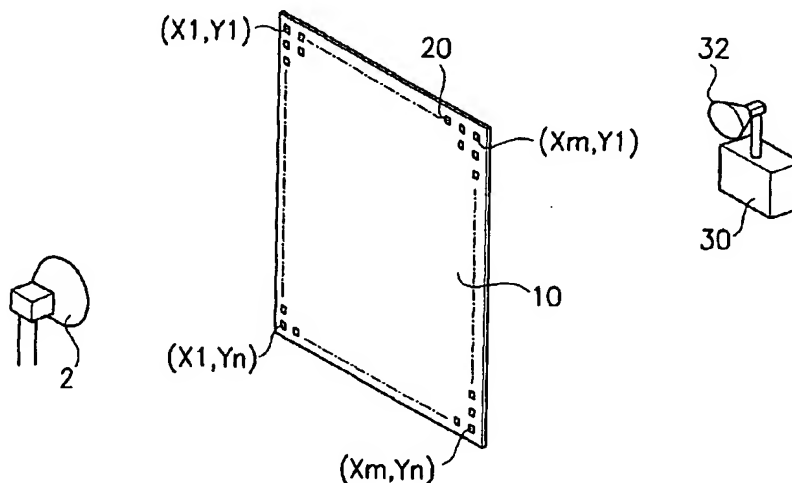
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- (71) Applicants (for all designated States except US): **THE EDUCATION & RESEARCH FOUNDATION FOR INDUSTRY, UNIVERSITY, AND RESEARCH INSTITUTE IN CHUNGNAM NATIONAL UNIVERSITY** [KR/KR]; 220 Gung-dong, Yuseong-gu, Daejeon-city 305-764 (KR). **AMPLET INC.** [JP/JP]; 4-2 Taito 3-chome, Taito-ku, Tokyo 110-0016 (JP). **VIGITA-SYSTEM INC.** [JP/JP]; Three-One Building 6F, 20-5, Shinyokohama 3-chome, Kohhoku-ku, Yokohama-city, Kanagawa 222-0033 (JP).
- (72) Inventors; and  
(75) Inventors/Applicants (for US only): **WOO, Jong-Myung** [KR/KR]; 108-201, Hanvit Apt., Eoeun-dong, Yuseong-ku, Daejeon-city 305-755 (KR). **KIM, Jong-Lae** [KR/KR]; 220 Gung-dong, Yuseong-gu, Daejeon-city 305-764 (KR).
- (74) Agent: **YOU ME PATENT & LAW FIRM**; Teheran Bldg., 825-33, Yoksam-dong, Kangnam-Ku, Seoul 135-080 (KR).
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(54) Title: SYSTEM AND METHOD FOR MEASURING RADIATION CHARACTERISTIC OF ANTENNA



(57) Abstract: An antenna measurement system is provided to measure the radiation characteristic of a source antenna (2), and obtain more correct far-field range data within a short period of time. The antenna measurement system includes a tester body placed apart from the source antenna (2) with a predetermined distance. A plurality of measurement modules (20) are arranged at the tester body in a predetermined pattern. Each measurement module has an IC chip (22) for processing positional information and measured values to generate relevant signals, and a tester antenna for receiving and transmitting the signals from the IC chip (22). Upon receipt of frequency signals from the source antenna (2), the tester antenna (24) generates induced power for driving the IC chip (22), and transmits the measured values for the frequency signals to the IC chip (22). A measurement controller (30) receives the signals from the tester antenna (24), and data-processes the positional information and the measured values of the respective measurement modules (20).